Application/Control No. Applicant(s)/Patent Under Reexamination 10/089,409 AIKOH ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 TAN X. DINH 2653 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 10-308,036 11-1998 **JAPAN** WEN XIN et al 369/274 Ν 0 Р Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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